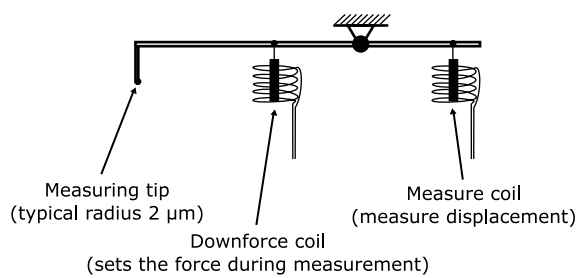


Mechanical Profilometer

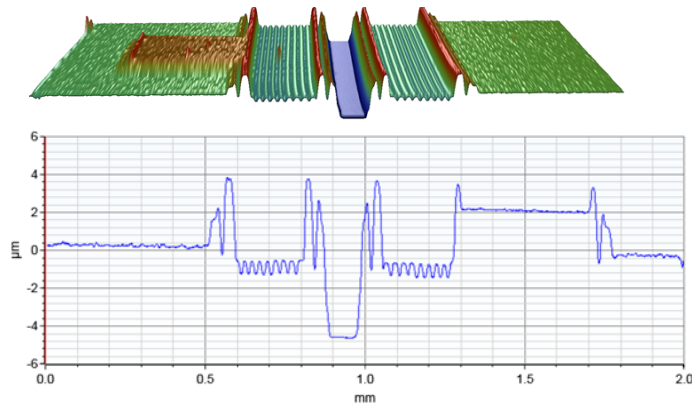
Bruker DektakXT

PRINCIPLE

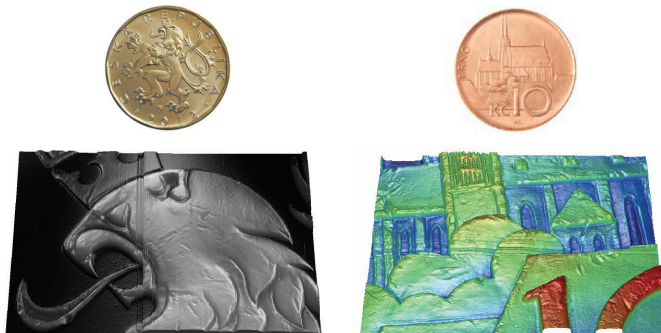
The DektakXT stylus surface profiler is an advanced thin and thick film step height measurement tool. In addition to profiling surface topography and waviness, the DektakXT system measures roughness in the nanometer range. Available with a standard manual sample-positioning stage or an optional automatic X-Y or theta stage, it provides a step-height repeatability of 5 Å (<0.6 nm). In addition to taking twodimensional surface profile measurements, the DektakXT system can produce three-dimensional measurements and analyses when equipped with the 3D Mapping Option.



RESULTS



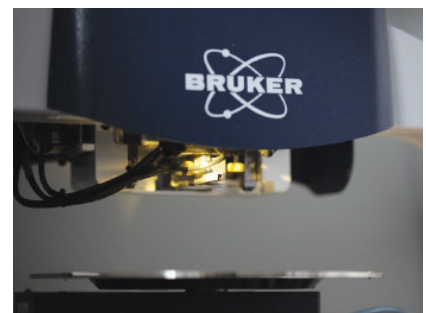
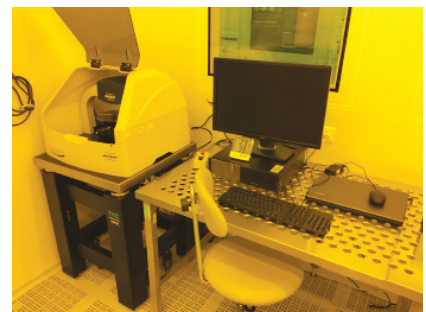
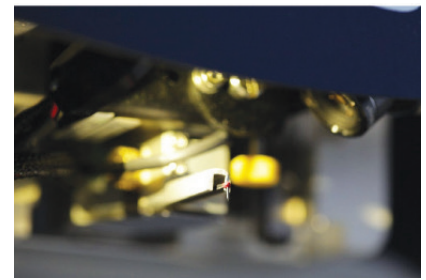
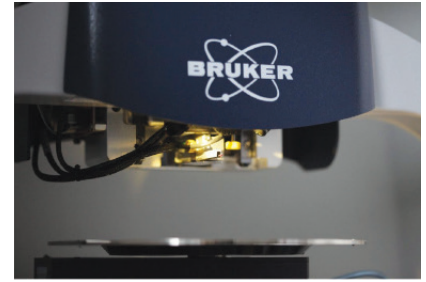
Surface topography of transistor measured by profilometer Dekta XT.



MORE INFO

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Web: <http://nano.ceitec.cz/mechanical-profilometer-bruker-dektak-xt-dektak/>



SPECIFICATION

Stage	diameter of 200 mm
Max. points	120
Repeatability	< 5 Å
Vertical resolution	1 Å
Pulse Freq.	1 - 200 kHz
Resolution	0.5 μm
Repetability	1 μm
Vertical Range	56 mm

